

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

CHATTING et al

Serial No. 10/556,455

Filed: November 10, 2005



Atty. Ref.: 36-1948

TC/A.U.: Unknown

Examiner:

For: IMAGE-SIZE DEPENDENT FACIAL CARICATURING

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March 14, 2006

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

Attention is directed to the attached PCT International Search Report for this application and each non-US patent reference cited therein. A PTO-1449 is also attached.

Official consideration and citation of each such reference is requested.

Respectfully submitted,

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Sheet 1 of 1

**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

36-1948

10/556,455

APPLICANT

CHATTING et al

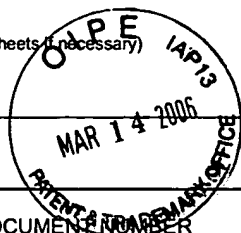
FILING DATE

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November 10, 2005

Unknown

(Use several sheets if necessary)

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2002/0018595 A1	02/2002	Kwak			

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
WO 01/59709 A1	08/2001	WIPO			

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	PCT International Search Report - August 5, 2004
	Murakam et al., "Dynamic Facial Caricaturing System based on the Gaze Direction of Gallery", AUTOMATIC FACE AND GESTURE RECOGNITION, 2000, PROCEEDINGS, FOURTH IEEE INTERNATIONAL CONFERENCE ON GRENOBLE, FRANCE 28-20 March 2000, Los Alamitos, CA, USA, IEEE COMPUT. SOC., US, 28 March 2000, pages 136-141
	Fujiwara et al., "On the Detection of Feature Points of 3D Facial Image and its Application to 3D Facial Caricature", 3-D DIGITAL IMAGING AND MODELING, 1999, PROCEEDINGS, SECOND INTERNATIONAL CONFERENCE ON OTTAWA, ONT., CANADA 4-8 October 1999, Los Alamitos, CA, IEEE COMPUT. SOC. US, 4 October 1999, pages 490-496

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.